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	APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
	10/664,722	09/17/2003	Jinru Bian	03019US	4382	
	75	590 12/01/2004		EXAM	EXAMINER	
	Rodel Holding	gs, Inc.		OWENS, DOUGLAS W		
	Suite 1300 1105 North Market Street Wilmington, DE 19899			ART UNIT	PAPER NUMBER	
				2811	-	
				DATE MAILED: 12/01/2004		

Please find below and/or attached an Office communication concerning this application or proceeding.

		th				
	Application No.	Applicant(s)				
	10/664,722	BIAN ET AL.				
Office Action Summary	Examiner	Art Unit				
	Douglas W Owens	2811				
The MAILING DATE of this communication Period for Reply	n appears on the cover sheet wit	h the correspondence address				
A SHORTENED STATUTORY PERIOD FOR R THE MAILING DATE OF THIS COMMUNICATI - Extensions of time may be available under the provisions of 37 C after SIX (6) MONTHS from the mailing date of this communication - If the period for reply specified above is less than thirty (30) days - If NO period for reply is specified above, the maximum statutory - Failure to reply within the set or extended period for reply will, by Any reply received by the Office later than three months after the earned patent term adjustment. See 37 CFR 1.704(b).	ON. FR 1.136(a). In no event, however, may a re on. , a reply within the statutory minimum of thirty period will apply and will expire SIX (6) MONT statute, cause the application to become ABA	ply be timely filed (30) days will be considered timely. HS from the mailing date of this communication. ANDONED (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on	21 October 2004.					
2a) ☐ This action is FINAL . 2b) ☑	This action is non-final.					
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is						
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.						
Disposition of Claims						
4)⊠ Claim(s) <u>1-10</u> is/are pending in the applic	 ✓ Claim(s) 1-10 is/are pending in the application. 4a) Of the above claim(s) 8-10 is/are withdrawn from consideration. ☐ Claim(s) is/are allowed. 					
4a) Of the above claim(s) 8-10 is/are without						
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>1-4 and 7</u> is/are rejected.						
7)⊠ Claim(s) <u>5,6</u> is/are objected to.	Claim(s) <u>5,6</u> is/are objected to.					
8) Claim(s) are subject to restriction and/or election requirement.						
Application Papers		·				
9) The specification is objected to by the Exa	nminer.					
10) The drawing(s) filed on is/are: a)	☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.					
Applicant may not request that any objection t	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).					
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).						
11)☐ The oath or declaration is objected to by t	he Examiner. Note the attached	Office Action or form PTO-152.				
Priority under 35 U.S.C. § 119						
 12) Acknowledgment is made of a claim for fo a) All b) Some * c) None of: 1. Certified copies of the priority docu 2. Certified copies of the priority docu 3. Copies of the certified copies of the 	ments have been received. ments have been received in Ap	oplication No				
application from the International B	•					
* See the attached detailed Office action for	, , , ,	eceived.				
Attachment(s)						
 Notice of References Cited (PTO-892) Dotice of Draftsperson's Patent Drawing Review (PTO-94) 	4) LInterview Su Paper No(s)	ummary (PTO-413) /Mail Date				
 Information Disclosure Statement(s) (PTO-1449 or PTO/S Paper No(s)/Mail Date 1/9/04. 		formal Patent Application (PTO-152)				

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DETAILED ACTION

Election/Restrictions

1. Applicant's election without traverse of the invention of group I, claims 1-7 in the reply filed on October 21, 2004 is acknowledged.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 3. Claims 1 4 and 7 are rejected under 35 U.S.C. 102(e) as being anticipated by US Patent Application Publication No. 2003/0102457 to Miller.

Regarding claims 1, 3 and 7, Miller teaches a composition for polishing semiconductor wafers, comprising 1 to 20% abrasive, which is included in the range of 0 to 30%, 0% inhibitor for a nonferrous metal, which is included in the range of 0 to 15%, between 1 to 20% of an oxidizer (paragraph [0020]), which is included in the range of 0 to 25, 0.01 to 0.1 mole/liter of acetic acid (paragraph [0020 – 0021] a guanidine salt), which is a tantalum removal agent having a concentration in the range of 0 to 10% 0.1% of a nonionic surfactant (paragraph [0024] 0.1% is part of the claimed range) that inherently suppresses removal rate of silicon carbide-nitride, since it is the same as the claimed substance, the nonionic surfactant having a hydrophilic group and

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a hydrophobic group (must be included since the substance is identical), the hydrophobic group having a carbon chain length of greater than three (paragraph [0024]).

With respect to the requirement of the surfactant suppressing "silicon carbidenitride removal rate at least 100 a[A]ngstroms per minute greater than its decrease in silicon nitride removal rate as measured with a microporous polyurethane polishing pad pressure measured normal to a wafer of 13.8 kPa", this is inherently taught by Miller, since the nonionic surfactant is identical. Moreover, this limitation does not appear to further define composition, but merely recites results from using it in a preferred manner.

Regarding claims 2 and 4, Miller teaches a composition, wherein the nonionic surfactant is alkyl polyethylene (paragraph [0024]).

Allowable Subject Matter

4. Claims 5 and 6 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Douglas W Owens whose telephone number is 571-272-1662. The examiner can normally be reached on Monday-Friday.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Eddie C Lee can be reached on 571-272-1732. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Douglas W. Owens

Douglo L. Owe

Patent Examiner